

[54] CIRCUIT TESTER

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[73] Assignee: Polytronics, Inc., Buffalo, N.Y.

[**] Term: 14 Years

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[52] U.S. Cl. D10/78

[58] Field of Search D10/75, 76, 77, 78,
D10/79, 80; 173/361; 324/588; 439/101, 102,
103, 104, 172

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[57] CLAIM

The ornamental design for a circuit tester, as shown.

DESCRIPTION

FIG. 1 is a bottom plan view of a circuit tester showing my new design;
FIG. 2 is a top plan view;
FIG. 3 is a front elevational view;
FIG. 4 is a rear elevational view;
FIG. 5 is a right side elevational view; and
FIG. 6 is a left side elevational view thereof.

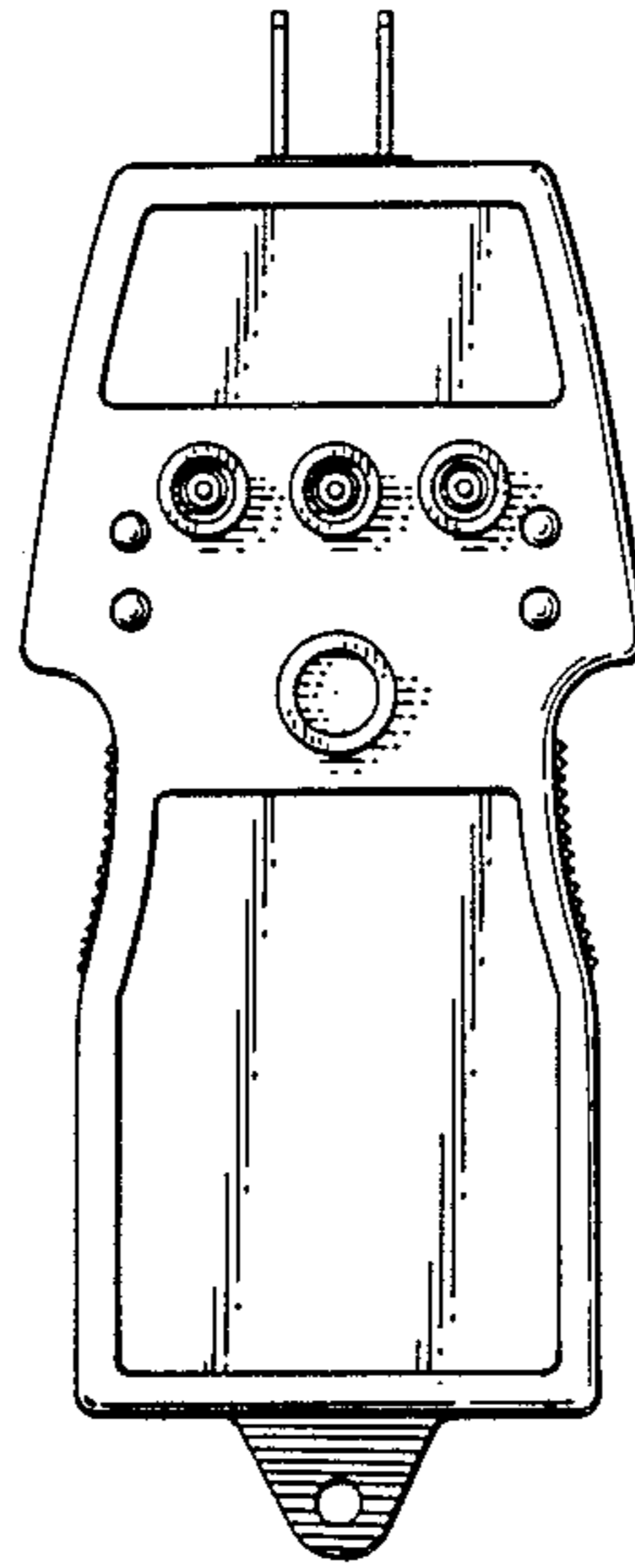


Fig. 1.

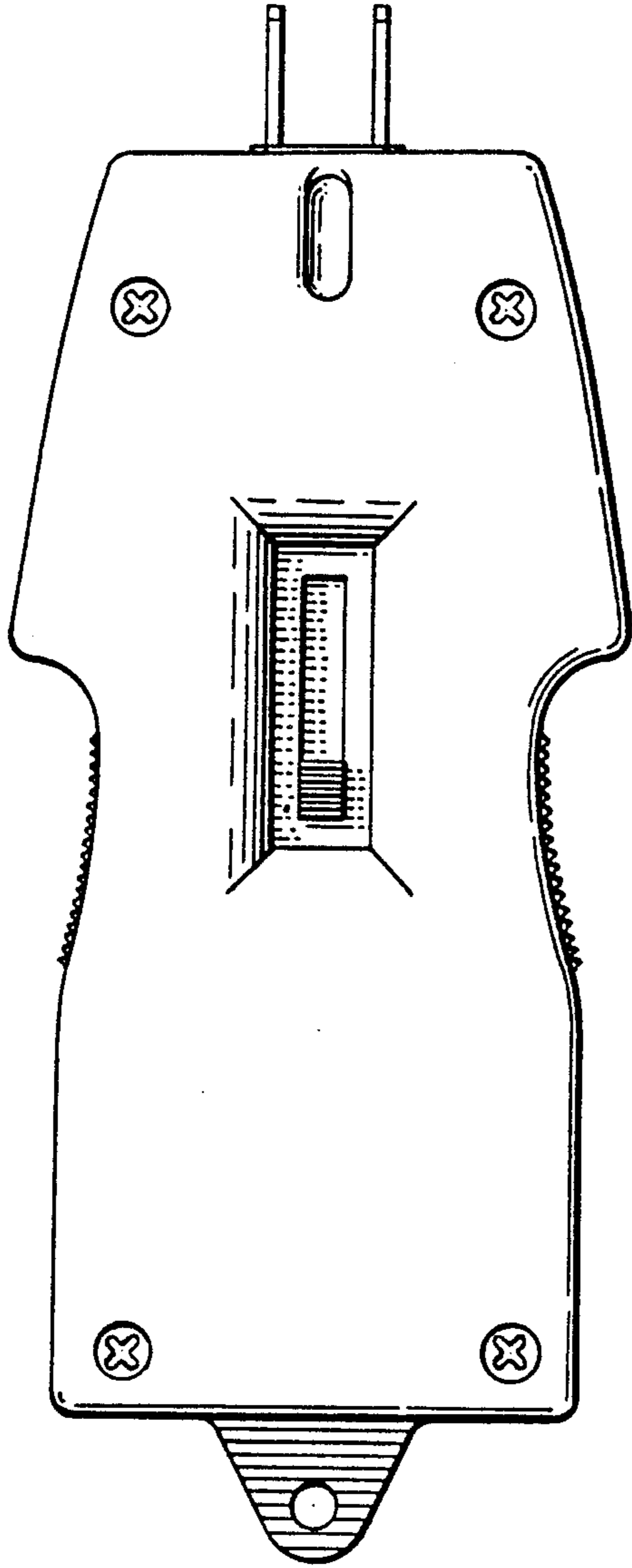


Fig. 2.

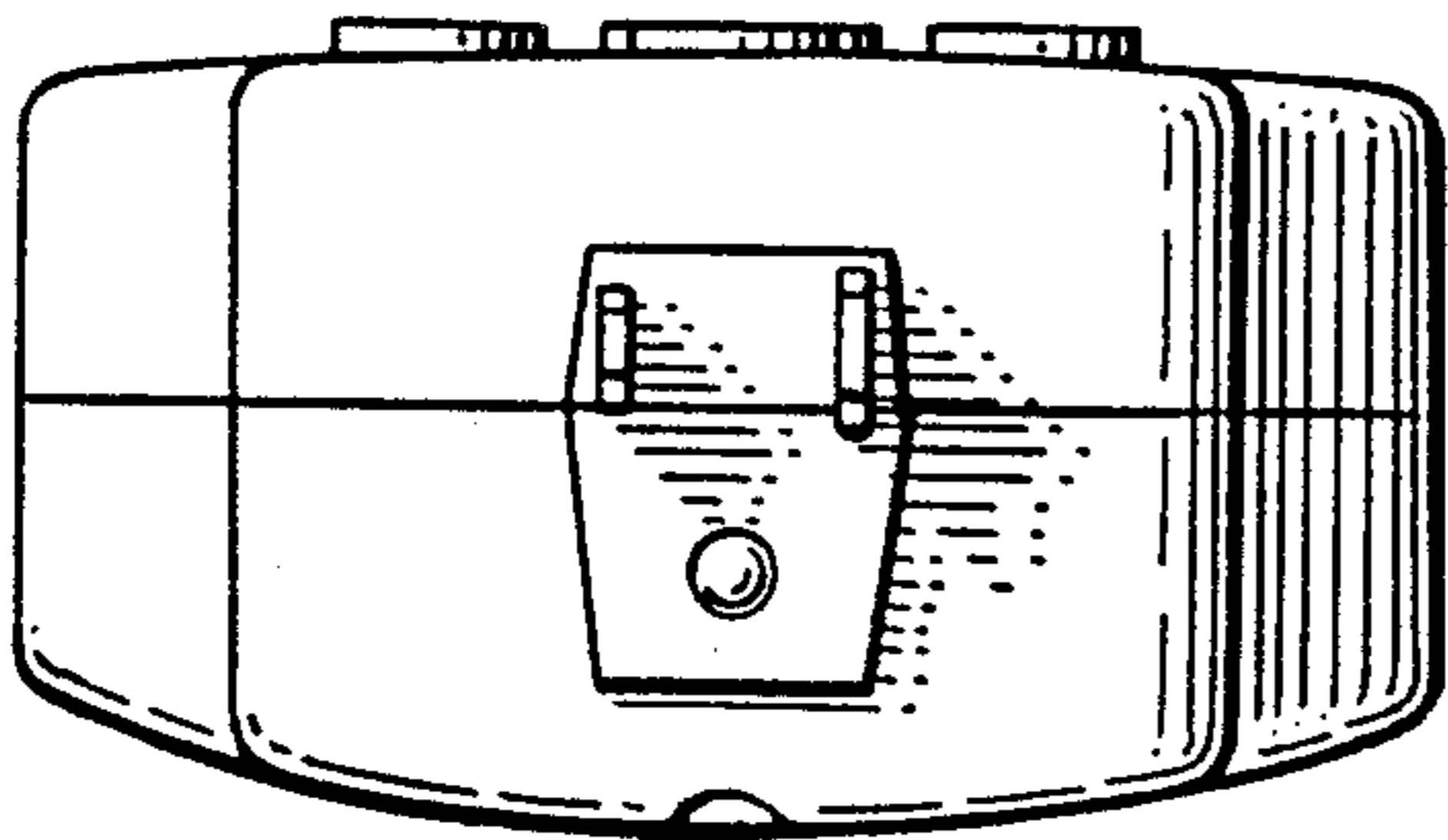
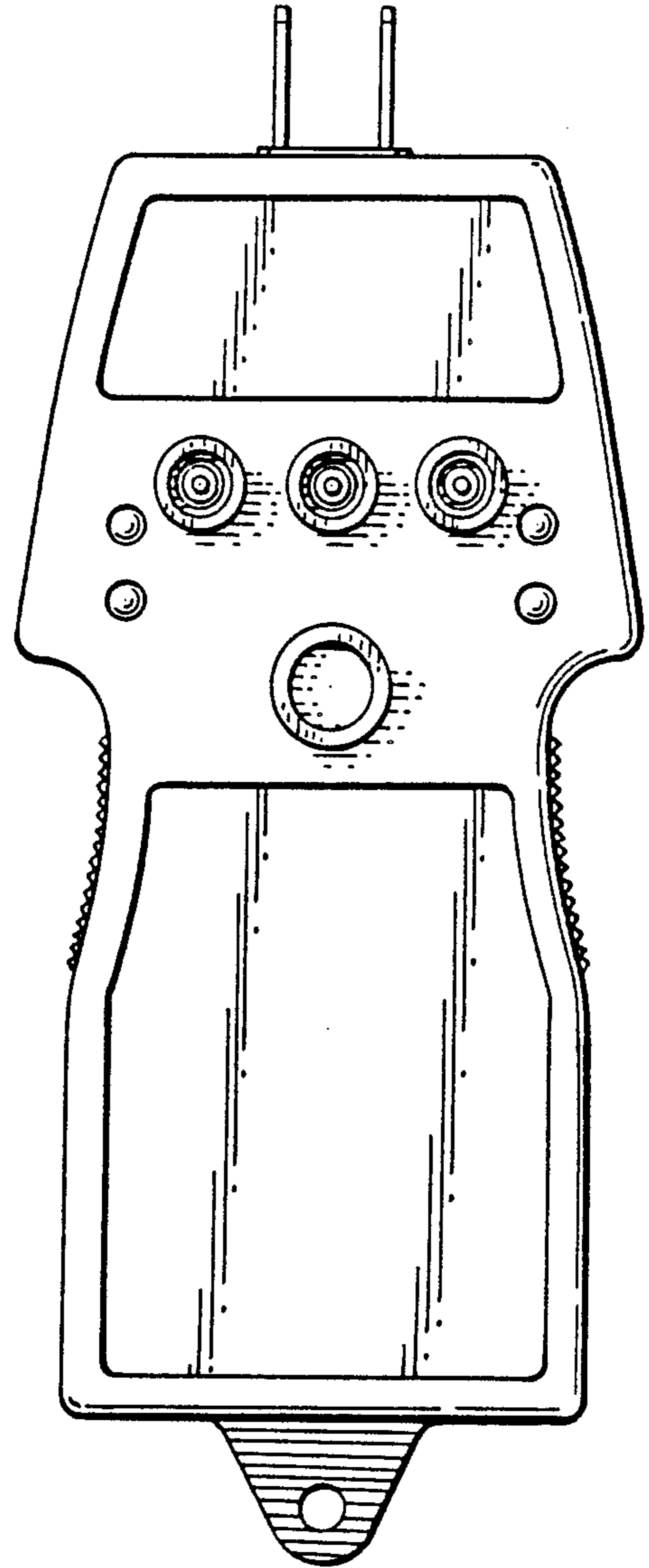


Fig. 3.

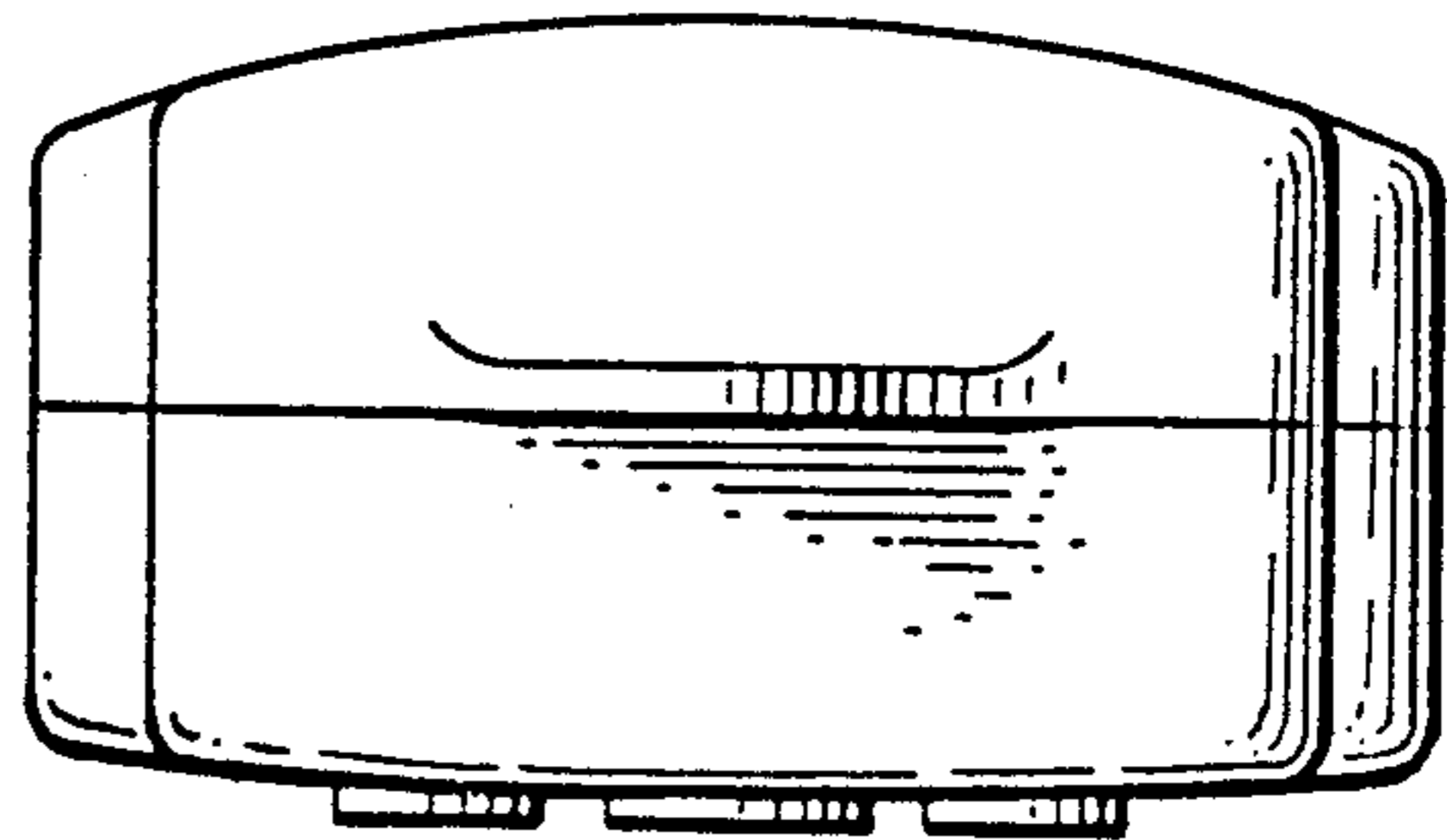


Fig. 4.

Fig. 5.

Fig. 6.

